Notice of References Cited

Application/Control No.	Applicant(s)/Pater	nt Under
10/719,317	Reexamination RAO, SUMITA	
Examiner	Art Unit	
Eric Wiener	2179	Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,479,476 A	12-1995	Finke-Anlauff, Andrea	455/566
*	В	US-5,521,896 A	05-1996	Bajorek et al.	369/53.18
*	υ	US-5,978,566 A	11-1999	Plank et al.	709/206
*	D	US-6,009,333 A	12-1999	Chaco, John	455/456.5
*	Е	US-6,209,011 B1	03-2001	Vong et al.	708/112
*	F	US-6,317,593 B1	11-2001	Vossler, Stephen P.	455/414.1
*	G	US-6,323,775 B1	11-2001	Hansson, Hans Magnus	340/636.1
*	н	US-2001/0049275 A1	12-2001	Pierry et al.	455/414
*	-	US-6,418,329 B1	07-2002	Furuya, Mami	455/566
*	J	US-2002/0138772 A1	09-2002	Crawford et al.	713/300
*	К	US-6,687,608 B2	02-2004	Sugimoto et al.	701/207
*	L	US-6,769,120 B1	07-2004	Rodriguez, Herman	718/100
*	М	US-6,831,444 B2	12-2004	Kobayashi et al.	320/136

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U w Х

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.	Applicant(s)/Pater	nt Under
10/719,317	Reexamination RAO, SUMITA	
Examiner	Art Unit	
Eric Wiener	2179	Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,831,970 B1	12-2004	Awada et al.	379/201.01
*	В	US-6,928,300 B1	08-2005	Skinner et al.	455/556.2
*	O	US-6,943,693 B2	09-2005	Kim, Dae-Hwan	340/636.1
*	D	US-6,961,859 B2	11-2005	Derocher et al.	713/320
*	Е	US-7,301,451 B2	11-2007	Hastings, David C.	340/539.12
*	F	US-7,315,882 B1	01-2008	Koch, Robert	709/206
*	G	US-7,362,854 B2	04-2008	Mcknight, Russell F.	379/210.01
*	Н	US-7,395,097 B2	07-2008	Perdomo et al.	455/574
*	_	US-7,400,229 B2	07-2008	Boss et al.	340/309.16
*	7	US-7,430,675 B2	09-2008	Lee, Michael M.	713/320
*	К	US-7,458,080 B2	11-2008	Parker et al.	719/318
*	L	US-7,496,352 B2	02-2009	Kaminsky et al.	455/412.2
*	М	US-7,502,634 B2	03-2009	Chi, Liang-Yu	455/566

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					7

	NON-PATENT DOCUMENTS					
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
Ī	v					
	w					
	x					

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice	of	References	Cited	
--------	----	------------	-------	--

Application/Control No. 10/719,317		Applicant(s)/Patent Under Reexamination RAO, SUMITA		
	Examiner	Art Unit		
	Eric Wiener	2179	Page 3 of 3	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,533,104 B2	05-2009	Hirose et al.	1/1
*	В	US-7,595,717 B2	09-2009	Boss et al.	340/309.16
*	С	US-7,606,584 B2	10-2009	Wang, Zhengwei	455/456.3
*	D	US-7,500,198 B2	03-2009	Mathews et al.	715/744
*	Е	US-6,590,590 B1	07-2003	Wen et al.	715/764
*	F	US-6,091,411 A	07-2000	Straub et al.	715/747
	G	US-		-	
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	٦	US-			
	м	US-			

FOREIGN PATENT DOCUMENTS

	FOREIGN FATENT DOCUMENTS					
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

	NON-PATENT DOCUMENTS					
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
Ī	v					
	w					
	×					

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.